WHAT IS CLAIMED IS:

1. An α-ray measuring apparatus comprising:

an α-ray detector including a plurality of semiconductor detectors;

an adder for adding output signals from said respective semiconductor detectors; and

a peak analyzer for analyzing an energy distribution of α-rays based on the addition of the output signals of said semiconductor detectors.

2. An α-ray measuring apparatus comprising:

an α-ray detector including a plurality of semiconductor detectors arranged on a plane surface;

an adder for adding output signals from said respective semiconductor detectors to generate an addition output signal;

an anticoincidence counter for anticoincidently counting the output signals from said respective semiconductor detectors; and

a peak analyzer for analyzing an energy distribution of α-rays based on an addition of the output signals of semiconductor detectors which are not anticoincidently counted.

3. An α-ray measuring apparatus comprising:

an α-ray detector including a plurality of semiconductor detectors arranged one above another;

an adder for adding output signals from said respective semiconductor detectors to generate an addition output signal;

an anticoincidence counter for anticoincidently counting the output signals of said respective semiconductor detectors; and

a peak analyzer for analyzing an energy distribution of α-rays based on an addition of the output signals of said respective semiconductor detectors which are not anticoincidently counted.

4. An α-ray measuring apparatus comprising:

an α-ray detector including a plurality of semiconductor detectors arranged on plane surfaces placed one above another;

an adder associated with each plane surface for adding output signals from said respective semiconductor detectors on said associated plane surface to generate an addition output signal;

an anticoincidence counter for anticoincidently counting the addition output signals of said respective sensors on said respective plane surfaces; and

a peak analyzer for analyzing an energy distribution of α-rays based on the addition output signals from said respective semiconductor detectors on said respective plane surfaces which are not anticoincidently counted.

5. An α-ray measuring apparatus according to claim 1, wherein:

said anticoincidence counter anticoincidently counts between an output signal of at least one of said

semiconductor detectors and output signals of the remainder of said semiconductor detectors.

6. An α-ray measuring apparatus according to claim 1, further comprising a data processor for specifying an energy range to be evaluated, and for displaying the result of analysis.

7. An α-ray measuring method comprising the steps of:

detecting α-rays using a plurality of semiconductor detectors;

adding output signals from said respective semiconductor detectors; and

analyzing an energy distribution of the α-rays based on an addition of the output signals from said semiconductor detectors.

8. An α-ray measuring method comprising the steps of:

detecting α-rays using a plurality of semiconductor detectors arranged on a plane surface;

adding output signals from said respective semiconductor detectors;

anticoincidently counting the output signals from said respective semiconductor detectors; and

analyzing an energy distribution of the α-rays based on an addition of the output signals from said semiconductor detectors which are not anticoincidently countered.

9. An α-ray measuring method comprising the

steps of:

detecting α-rays using a plurality of semiconductor detectors arranged one above another;

adding output signals from said respective semiconductor detectors;

anticoincidently counting the output signals of said respective semiconductor detectors; and

analyzing an energy distribution of the α-rays based on an addition of the output signals from said semiconductor detectors which are not anticoincidently countered.

10. An α-ray measuring method comprising the steps of:

detecting α-rays using a plurality of semiconductor detectors arranged on plane surfaces placed one above another;

adding output signals from said respective semiconductor detectors on each of said plane surfaces;

anticoincidently counting the output signals from said respective semiconductor detectors on said respective plane surfaces; and

analyzing an energy distribution of the α-rays based on an addition of the output signals from said semiconductor detectors on each of said plane surface which are not anticoincidently countered.